



3D-IC Designs for Power, Performance, and Cost

Brandon Wang

Group Director, Strategic Program at Cadence

04-23-2015

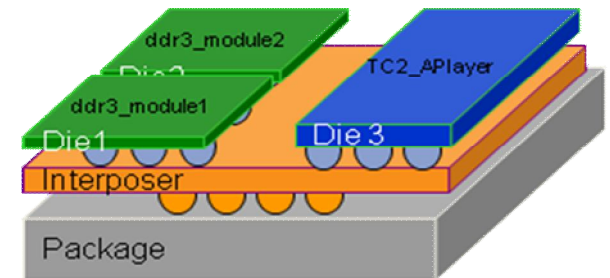
cādence[®]

Short-, medium-, and long-term path to 3D-IC



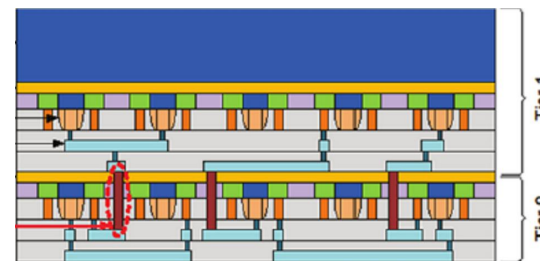
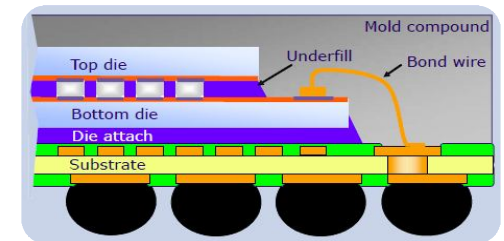
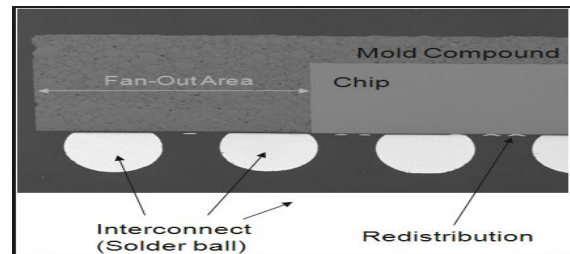
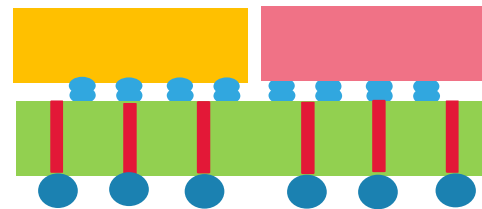
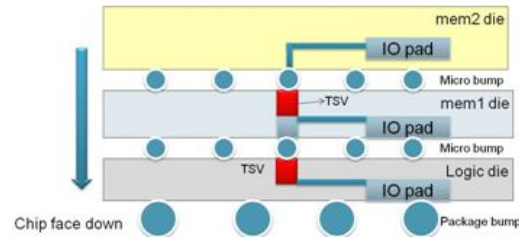
2.5D Silicon Interposer for Performance Driven Applications

- Interposer enables high performance/high bandwidth applications through massive interconnects among dies, particularly logic dies and memory dies;
- TSVs in SI Interposer die provide shorter routes for high speed signals, and deliver adequate power/ground connections to both logic and memory dies;
- Metal mesh and MiM Cap in Silicon interposer further enhance the performance through better SI and PI
- Silicon interposer as better heat conductor for improved thermal dissipation for higher performance

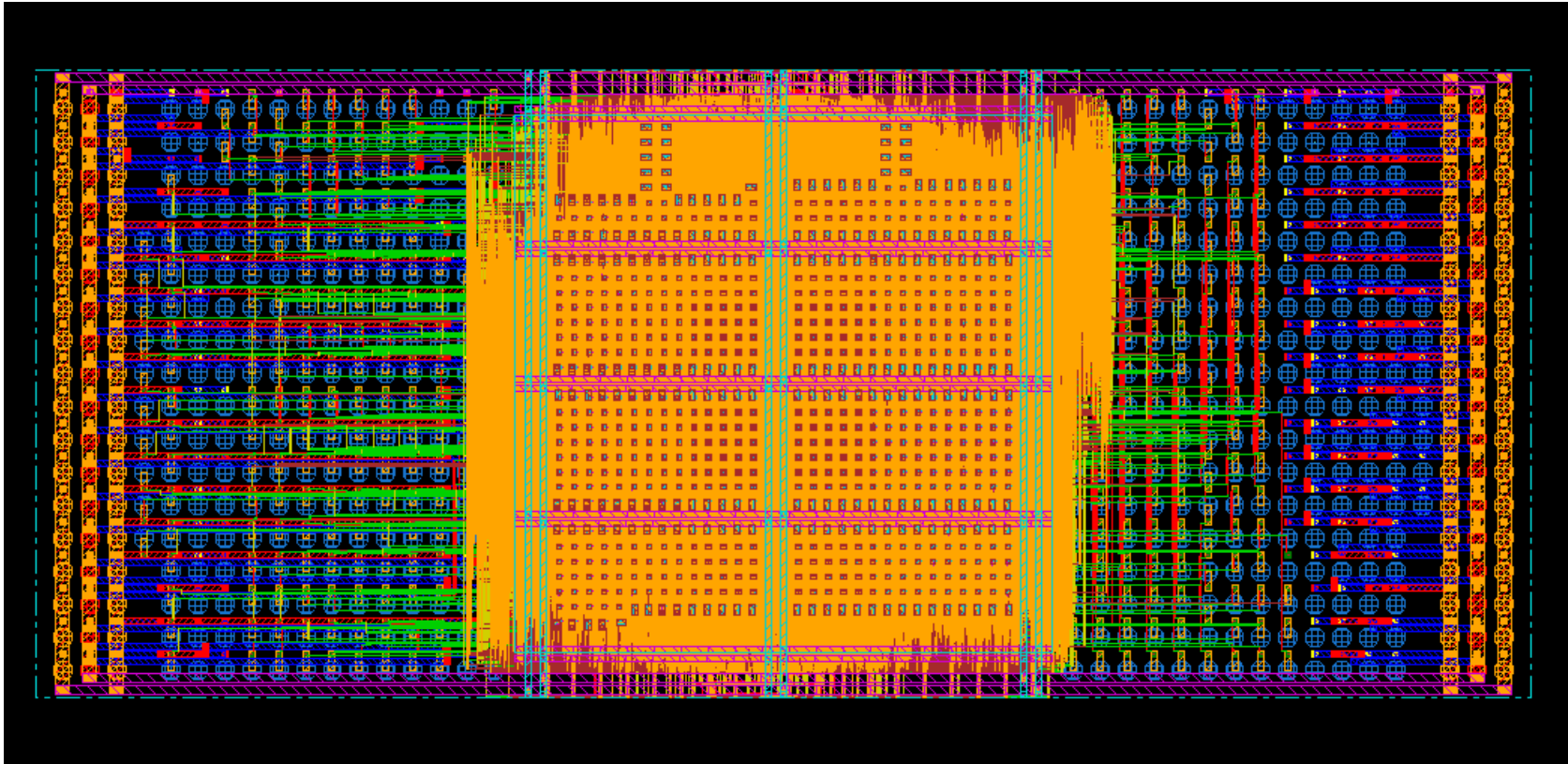


3D Stack and/or Monolithic 3D for lower cost

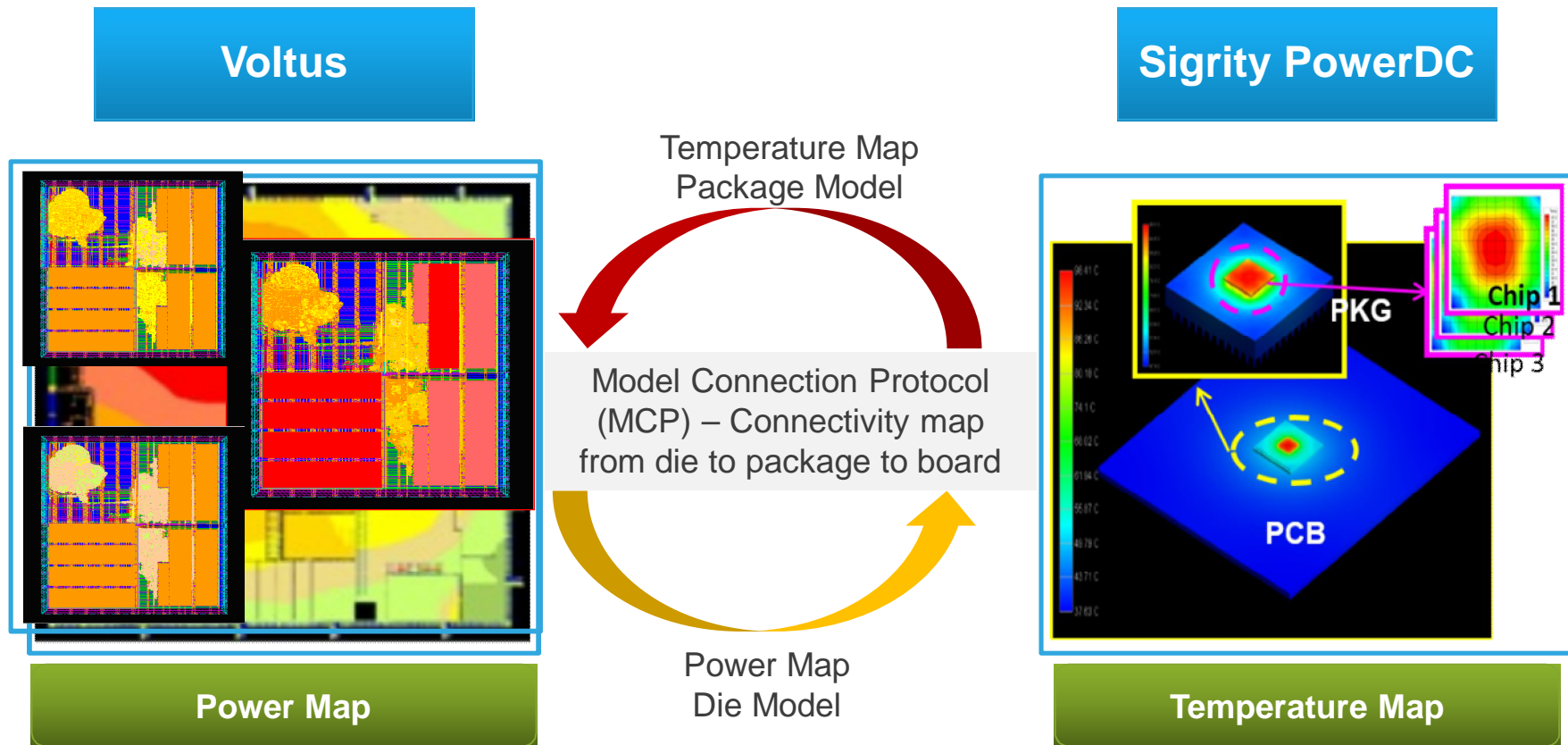
- No additional SI Interposer cost
- TSV-Less Integration
 - No wafer thinning, less yield loss
 - Face2face uBump connection for multi-die stack
 - Integrated Fan out WLP
- Monolithic 3D-IC



3D-IC using uBumps for inter-die P&R Optimization using EDI/Innovus



Multi-Dies-package-board thermal co-simulation



- Sigrity PowerDC computes Temperature map including multiple dies, package and board
- Voltus computes temperature dependent Power map of each die (leakage, dynamic)
- Iterate co-simulation until results converge (equilibrium, transit)

Summary

- Different 3D-IC integration technologies are needed for high performance centric, or low cost applications;
- All 3D-IC integration technologies, whether high performance, or lower cost, will reduce system power consumption;
- IoT, Wearable in consumer applications will drive the TSV less 3D integration technologies such as InFO WLP to mass production;
- Monolithic 3D integration will both bring even higher performance and lower power in smaller form factor in near future;
- Implementation method varies for different 3D integration technologies, but electrical and thermal co-analysis are commonly required at die-package at plan/design phases.

cā dence[®]